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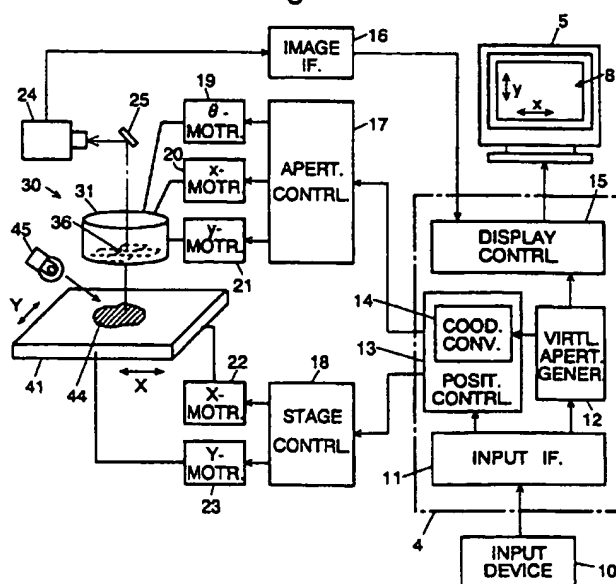
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(54) Abstract Title

Aperture setting for infrared microscope using virtual aperture superimposed on sample image

(57) An image of a virtual aperture (51, Figure 3A) is superimposed on an image of a microscope sample (50, Figure 3A) on the screen 8 of a display. Looking at the screen, an operator gives commands to a virtual aperture generator 12 to set the image 51 of the virtual aperture at a desired position, dimensions and orientation with respect to the image of the sample 50, using mouse or other input device. When the setting operation is finished, information representing the position of the image of the virtual aperture 51 with respect to the image of the sample 50 is obtained from the virtual aperture generator 12 and the sample stage driver 18, or from the display controller 15. The information is converted to corresponding values of the actual sample stage 41 and the aperture 36, and control values for bringing the the actual aperture 36 to the target position of the virtual aperture 51 and the image 50 of the sample on the screen set by the operator.

Fig. 2



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